

Examiner-Initiated Interview Summary	Application No. 09/485,298	Applicant(s) YAMAMOTO ET AL.	
	Examiner Young J. Kim	Art Unit 1637	

All Participants:

(1) Young J. Kim.

(2) Thomas Siepmann.

Status of Application: After-Final

(3) _____.

(4) _____.

Date of Interview: 2/15/00

Time: 8:55 a.m.

Type of Interview:

- ☒ Telephonic
☐ Video Conference
☐ Personal (Copy given to: ☐ Applicant ☐ Applicant's representative)

Exhibit Shown or Demonstrated: ☐ Yes ☒ No

If Yes, provide a brief description:

Part I.

Rejection(s) discussed:

n/a

Claims discussed:

n/a

Prior art documents discussed:

Gelfand et al. (U.S. Patent No. 6,693,517; IDS reference AA)

Part II.

SUBSTANCE OF INTERVIEW DESCRIBING THE GENERAL NATURE OF WHAT WAS DISCUSSED:

See Continuation Sheet

Part III.

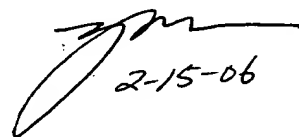
- ☐ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview directly resulted in the allowance of the application. The examiner will provide a written summary of the substance of the interview in the Notice of Allowability.
☒ It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview did not result in resolution of all issues. A brief summary by the examiner appears in Part II' above.

**YOUNG J. KIM
PATENT EXAMINER**

(Examiner/SPE Signature)

(Applicant/Applicant's Representative Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: Mr. Siepmann was advised that the reference(s) cited in the IDS received on November 23, 2005, said IDS received after a Final Rejection, said IDS filed with a statement under 1.97(e) and fee under 1.17(p), necessitates a new ground of rejection. Since the IDS was filed with a statement under 1.97(e), Mr. Siepmann was advised that the Office Action would be made Non-Final.

Handwritten signature of Young J. Kim in black ink, consisting of a stylized 'YJ' followed by a horizontal line.

2-15-06
YOUNG J. KIM
PATENT EXAMINER